

Ahmet Furkan Kurban

1801042674

Homework 1

Amel

Answers

1) A) For Wafer-X : Wafer Area = $\pi r^2 = 3.14 \times 8 \times 8 = 200.96 \text{ cm}^2$
Die Area = $\frac{\text{Wafer Area}}{\text{Dies per wafer}} = \frac{200.96 \text{ cm}^2}{64} = 3.14 \text{ cm}^2$

For Wafer-Y

Wafer Area = $\pi r^2 = 3.14 \times 10 \times 10 = 314 \text{ cm}^2$
Die Area = $\frac{\text{Wafer Area}}{\text{Dies per wafer}} = \frac{314}{100} = 3.14 \text{ cm}^2$

B) For wafer-X yield = $\frac{1}{(1 + (\text{Defects Per Area} \times \text{Die Area} / 2))^2}$
 $= \frac{1}{(1 + (0.02 \times \frac{3.14}{2}))^2} = \frac{1}{(1 + (0.02 \times 1.57))^2}$
 $= 0.9401$

cost per die = $\frac{\text{cost per wafer}}{\text{Dies per wafer} \times \text{yield}} = \frac{15}{64 \times 0.9401}$
 $= \frac{15}{60.16} = 0.249$

For wafer-Y yield = $\frac{1}{(1 + (\text{Defects Per Area} \times \text{Die Area} / 2))^2}$
 $= \frac{1}{(1 + (0.03 \times 1.57))^2} = \frac{1}{(1 + (0.0471))^2} = 0.912$

cost per die = $\frac{\text{cost per wafer}}{\text{Dies per wafer} \times \text{yield}} = \frac{24}{100 \times 0.912}$
 $= \frac{24}{91.2} = 0.263$

	New Table Value	Diameter	cost per wafer	Dies Per wafer	Defects Per Area
C)	Wafer-X	16cm	12	70.4	0.023/cm
	Wafer-Y	20cm	19.2	110	0.0345/cm

For wafer-X: wafer Area = $\pi r^2 = 3.14 \times 8 \times 8 = 200.96 \text{ cm}^2$

$$\text{Die Area} = \frac{\text{wafer Area}}{\text{Dies Per wafer}} = \frac{200.96 \text{ cm}^2}{70.4} = 2.85 \text{ cm}^2$$

$$\begin{aligned} \text{Yield} &= \frac{1}{(1 + (\text{Defects Per Area} \times \text{Die Area} / 2))^2} \\ &= \frac{1}{(1 + (0.023 \times \frac{2.85}{2}))^2} = \frac{1}{(1 + 0.032)^2} \\ &= \frac{1}{1.065} = 0.938, \end{aligned}$$

$$\begin{aligned} \text{cost per die} &= \frac{\text{cost per wafer}}{\text{Dies Per wafer} \times \text{Yield}} = \frac{12}{70.4 \times 0.938} \\ &= \frac{12}{66.04} = 0.182, \end{aligned}$$

For wafer-Y: wafer Area = $\pi r^2 = 3.14 \times 10 \times 10 = 314 \text{ cm}^2$

$$\text{Die Area} = \frac{\text{wafer Area}}{\text{Dies Per wafer}} = \frac{314}{110} = 2.85 \text{ cm}^2$$

$$\begin{aligned} \text{Yield} &= \frac{1}{(1 + (\text{Defects Per Area} \times \text{Die Area} / 2))^2} \\ &= \frac{1}{(1 + (0.0345 \times \frac{2.85}{2}))^2} = \frac{1}{(1 + 0.0491)^2} \\ &= \frac{1}{1.100} = 0.909, \end{aligned}$$

$$\begin{aligned} \text{cost per die} &= \frac{\text{cost per wafer}}{\text{Dies Per wafer} \times \text{Yield}} = \frac{19.2}{110 \times 0.909} \\ &= \frac{19.2}{99.99} = 0.192, \end{aligned}$$

Both wafer-X's and wafer-Y's cost per die is 1.369 times less than previous year.

2)

R Type Instructions = 3×10^8

Almet Furkan Kalkan

1801042674

Almet

L Type Instructions = 5×10^8

J Type Instructions = 2×10^8

A) $P_1 = 3 \times 3 \times 10^8 + 5 \times 10^8 \times 4 + 2 \times 10^8 \times 3 = 32 \times 10^9$ clock cycles
 $P_2 = 3 \times 3 \times 10^8 + 5 \times 10^8 \times 3 + 2 \times 10^8 \times 3 = 30 \times 10^9$

B) $P_1 = \frac{32 \times 10^9}{1 \times 10^9} = 3.2 \rightarrow \text{Average CPI}$
 $P_2 = \frac{30 \times 10^9}{1 \times 10^9} = 3$

C) Execution time For P_1 : $\frac{\text{Instruction count} \times \text{CPI}}{\text{clock Rate}}$

$= \frac{1 \times 10^9 \times 3.2}{3 \times 10^9} = \frac{3.2}{3} = 1.066$

Execution time For P_2 : $\frac{\text{Instruction count} \times \text{CPI}}{\text{clock Rate}}$

$= \frac{1 \times 10^9 \times 3}{1.5 \times 10^9} = 2 \text{ sec}$

D) P_1 is $\frac{2.066}{1.066} = 1.975$ times faster than P_2 .

or.

$\frac{\text{Exp1}}{\text{Exp2}} = \frac{3.2 \text{ ns} \times \frac{1}{2.8 \text{ GHz}}}{3 \text{ ns} \times \frac{1}{1.8 \text{ GHz}}} = \frac{116}{3} = 0.533$